## **Supporting Information**

One-pot synthesis of novel ligand-free Tin(II)based hybrid metal halide perovskite quantum dots with high anti-water stability for solution-processed UVC photodetectors

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**Figure S1.** (a) XPS of the TBASnCl<sub>3</sub> QDs film; (b) The structure diagram of the TBASnCl<sub>3</sub> QDs.



Figure S2. Schematic diagrams of the processing procedure for lateral photodetectors  $Au/TBASnCl_3/Au$ .



**Figure S3.** (a) EDS and (b) analysis of the TBASnCl<sub>3</sub> QDs film.



**Figure S4.** (a) PL spectra and (b) XRD patterns of TBASnCl<sub>3</sub> QDs film after depositing in the ambient atmosphere with an air humidity of 60 % just after its fabricating and after one week, respectively.



**Figure S5** Experimental and calculated powder X-ray diffraction patterns of the as-prepared TBASnCl<sub>3</sub> powder and TBASnCl<sub>3</sub> thin films on glass surface.



**Figure S6** (a) XRD patterns of the TBASnCl<sub>3</sub> powder; (b) XRD patterns of TBASnCl<sub>3</sub> QDs film after annealing at 70 $^{\circ}$ C. The inset shows the XRD patterns of TBASnCl<sub>3</sub> QDs film after its magnification.



**Figure S7.** XRD patterns of the TBASnCl<sub>3</sub> QDs film after annealing at different temperature. (a) 70 °C; (b) 80 °C and (c) 100 °C. (d) XRD patterns of the TBASnCl<sub>3</sub> QDs film after different annealing times at 70 °C.



**Figure S8.** UPS spectra of the  $TBASnCl_3$  film. (a) The secondary edge region and (b) the HOMO region of the  $TBASnCl_3$  QDs film.